

PRODUCT/PROCESS CHANGE NOTIFICATION PCN 10549 – Additional information

ASE Kaohsiung (Taiwan) additional source for LQFP 20x20 package products

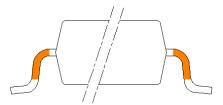
MDG - Microcontrollers Division (MCD)

What are the changes?

Changes described in the below table:

	Existing back-end site			Added back-end site	
Assembly site		Amkor ATP Philippines			
7 locomory cito	Annoi Att Thiippines				Taiwan
Leadframe	Copper Frame Spot Ag Copper Fram			Conner Frame	Copper Frame Spot
Louditaine				Обррен наше	Ag
Leadfinishing (1)	Pure Tin (e3)			PPF (e4)	Pure Tin (e3)
Resin (2)	Sumitomo EME-0	Sumitomo EME-G631SHQ Sumitomo EME-G631		EME-G631HO	Sumitomo EME-
rcom (z)	Sumitomo Livie-Gos ISITQ		Sumitomo Livie-Gos mig		G631SH
Glue	Ablestik 3230	Evertech AP4200		Sumitomo	Sumitomo CRM
Olde	Ablestik 3230 Evert			CRM1076YB	1076WA
Enhanced traceability	No			Yes	
in marking	140				(2 digits)

(1) Lead color and surface finish change depending on leadfinishing.



(2) Package darkness changes depending on molding compound.

How can the change be seen?

The standard marking is:

e4
PPI LL WX

PP code indicates the assembly traceability plant code.

Please refer to the <u>DataSheet</u> for marking details.

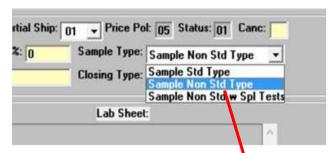
The marking is changing as follows:

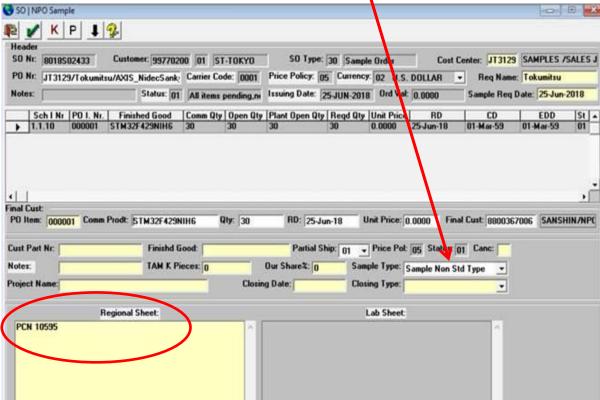
Existing		Additional		
PP code	Fab	PP code	Fab	
7B	Amkor ATP Philippines	AA	ASE Kaohsiung Taiwan	

How to order samples?

For all samples request linked to this PCN, please:

- place a <u>Non-standard</u> sample order (choose Sample Non Std Type from pull down menu)
- insert the PCN number "PCN 10549" into the NPO Electronic
 Sheet/Regional Sheet
- request sample(s) through Notice tool, indicating a single Commercial
 Product for each request







RER1810 for PCN 10548, PCN10549 & PCN10689 ASE Kaohsiung (Taiwan) additional source for LQFP 7x7/10x10/14x14/20x20

Reliability Evaluation Plan

January 30th, 2019

MDG MCD Quality & Reliability Department



RER1810 ASE Kaohsiung (Taiwan) additional source for LQFP 7x7/10x10/14x14/20x20 - Package Test Vehicles & Strategy

Test vehicles are selected by Change Review Board based on key parameters such as die size and volumes allowing to qualify the entire product family in LQFP. Similarity strategy will be applied to cover all combinations of Diffusion Plant, Diffusion Process and LQFP packages listed below:

- TSMC 0.18µm / TSMC M10 / TSMC 90 / Crolles CR300 M10 / Crolles CR300 M40 / Rousset R8 F9GO2 / Rousset R8 F9GO2s diffusion process
- LQFP7x7 / 10x10 / 14x14 / 20x20 on the same assembly line and using same materials for bonding wires, die attach glue and mold compound

Package line	Assembly Line	Package	Device (Partial RawLine Code)	Diffusion Plants & Process	Number of Reliability Lots
LQFP	LQFP 7*7	48L	STM32(5B*422)	TSMC 0.18µm	1
			STM8(5B*764)	Rousset R8 F9GO2	1
	LQFP 10*10	64L	STM32(5W*411)	TSMC M10	1
			STM32(5W*417)	Rousset R8 F9GO2s	1
	LQFP 14*14	100L	STM32(1L*436)	Rousset R8 F9GO2	1
			STM32(1L*448)	TSMC 0.18µm	1
			STM32(1L*411)	TSMC M10	1
			STM32(1L*435)	TSMC 90nm	1
	LQFP 20*20	144L	STM32(1A *450)	Crolles CR300 M40	1
			STM32(1A *413)	Crolles CR300 M10	1
			STM32(1A *414)	TSMC 0.18µm	1



RER1810 ASE Kaohsiung (Taiwan) additional source for LQFP 7x7/10x10/14x14/20x20 - Package Reliability Trials 3

Reliability Trial & Standard		Test Conditions	Pass Criteria	Unit per Lot	Lot qty
PC	Pre Conditioning: Moisture Sensitivity Jedec Level 3 J-STD-020/ JESD22-A113	Bake (125°C / 24 hrs) Soak (30°C / 60% RH / 192 hrs) for level 3 Convection reflow: 3 passes	3 passes MSL3	308	1 per device
Uhast(*)	UnBiased Highly Accelerated Temperature and Humidity Stress JESD22 A118	130°C, 85%RH, 2 atm	96h	77	1 per device(**)
TC(*)	Thermal Cycling JESD22 A104	-50°C, +150°C Or equivalent -65°C +150°C	1000Cy 500Cy	77	1 per device(**)
THB (*) Or HAST (*)	Temperature Humidity Bias JESD22-A101 Or Biased Highly Accelerated temperature & humidity stress JESD22 A110	85°C, 85% RH, bias Or 110°C, 1.2 atm , 85% RH bias	1000h Or 264h	77	1 per device(**)
HTSL (*)	High Temperature Storage Life JESD22 A103	150°C- no bias	1000h	77	1 per device(**)
Construction analysis	JESD 22B102 JESDB100/B108	including Solderability, Physical dimensions for LQFP10*10, LQFP14*14, LQFP20*20	15 10		1 per device FE techno and package
ESD	ESD Charge Device Model ANSI/ESD STM5.3.1 Or JESD22-C101 Or JEDEC JS-002	Aligned with device datasheet	250V to 500V	3	1 per device



^(*) tests performed after preconditioning

^(**) except die 422

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